

PATENT APPLICATION

Sheet 1 of 1

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APPLICANT

Christopher K. Sutton et al

FILING DATE

11/19/2001

GROUP

2863

JOINT OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION DISCLOSURE
STATEMENT

(Use several sheets if necessary)

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	*	DOCUMENT NUMBER	DATE	NAME
tl		5,206,582	Apr 27, 1993	Ekstedt, Thomas W. et al

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	TRANSLATION	
					YES	NO
tl		EP 1 308 737	07.05.2003	Sutton, Christopher	x	
tl		WO 99/47937	23 Sept 1999	Hansen, Peter, L	x	

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

tl	XP002259312, Klinger, Motti, "Reusable Test Executive and Test Programs Methodology and Implementation Comparison Between HP Vee and Labview", Proceedings of the Autotestcon 1999, IEEE, 30 August 1999 - 2 September 1999, pages 305-312, page 307, col 1, paragraph 1-col 2, last paragraph; page 305, col 1, paragraph 2-page 306, col. 2, last paragraph.
tl	Thompson, Kirk D., "COM-Based Test Foundation Framework", Autotestcon '99, IEEE Systems Readiness Technology Conference, 1999, IEEE San Antonio, TX, USA 30 Aug-2 Sept. 1999, Piscataway, NJ, USA, IEEE, US, 30 August 1999, pages 19-25, XP010356126, ISBN: 0-7803-5432-X; Figures 1, 2; pg 19, col 2, paragraph 2 - pg 21, col 1, paragraph 1; pg 22, col 1, paragraph 1-col 2, paragraph 2.
tl	Fertitta, K. G. et al, "The Role of Activex and COM in ATE", Autotestcon '99, IEEE Systems Readiness Technology Conference, 1999, IEEE San Antonio, TX, USA 30 Aug-2 Sept 1999, Piscataway, NJ, USA, IEEE, US, 30 August 1999, pages 35-51, XP010356128, ISBN: 0-7803-5432-X, pg 35, col 2, paragraph 4-pg 40, col 2, paragraph 8.

EXAMINER

DATE CONSIDERED

Tugler

3-8-2004

* Copies of these references are not enclosed pursuant to 37 CFR 1.98(d). (See accompanying IDS)